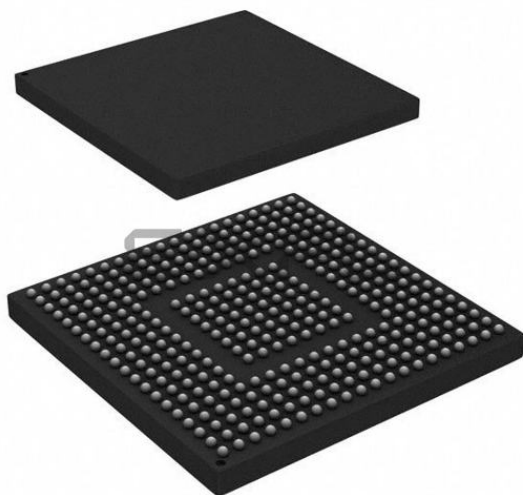




Welcome to [E-XFL.COM](#)

Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Active
Core Processor	ARM® Cortex®-A5 + Cortex®-M4
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	500MHz, 167MHz
Co-Processors/DSP	Multimedia; NEON™ MPE
RAM Controllers	LPDDR2, DDR3, DRAM
Graphics Acceleration	Yes
Display & Interface Controllers	DCU, GPU, LCD, VideoADC, VIU
Ethernet	10/100Mbps (2)
SATA	-
USB	USB 2.0 OTG + PHY (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 85°C (TA)
Security Features	-
Package / Case	364-LFBGA
Supplier Device Package	364-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mvf60nn152cmk50

3.3.1 Example

This is an example of an attribute:

Symbol	Description	Min.	Max.	Unit
CIN_D	Input capacitance: digital pins	—	7	pF

3.4 Definition: Rating

A *rating* is a minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure:

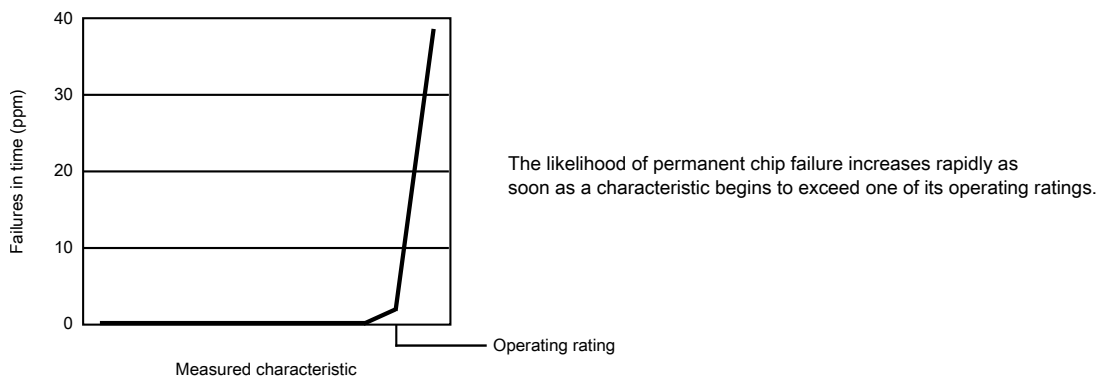
- *Operating ratings* apply during operation of the chip.
- *Handling ratings* apply when the chip is not powered.

3.4.1 Example

This is an example of an operating rating:

Symbol	Description	Min.	Max.	Unit
V _{DD}	1.0 V core supply voltage	−0.3	1.2	V

3.5 Result of exceeding a rating



6.2 Nonswitching electrical specifications

6.2.1 VREG electrical specifications

6.2.1.1 HPREG electrical characteristics

Table 2. HPREG electrical characteristics

Parameters	Min	Typ	Max	Unit	Comments
Power supply	3.0	3.3	3.6	V	-
Current Consumption	-	1.2	1.5	mA	@ no load
	-	2.0	2.5	mA	@ full load
Output current capacity	-	600	1200 ¹	mA	DC load current
Output voltage @ no load		1.23	1.26	V	
Output voltage @ full load	1.20	1.21		V	
External decoupling cap	4.7		-	μF	-
	0.05		0.1	Ohms	ESR of external cap
			20	mOhms	Total effective PAD+PCB trace resistances
PSRR with 4.7μF output cap					
@ DC @noload			-48	dB	
@ DC @full load			-40		
@ worst case any frequency			-20		

1. This is peak and not continuous maximum value.

6.2.1.2 LPREG electrical characteristics

Table 3. LPREG electrical characteristics

Parameters	Min	Typ	Max	Unit	Comments
Power supply	3.0	3.3	3.6	V	
Current Consumption	350	400		μA	@ no load
	-	500	650	μA	@ full load
Output current capacity		100	200	mA	DC load current
Output voltage @ no load		1.22	1.240	V	
Output voltage @ full load	1.180			V	
External decoupling cap	4.7			μF	
	0.05		0.1	Ohms	ESR of external cap
			20	mOhms	Total PAD+PCB trace resistance

Table continues on the next page...

**Table 3. LPREG electrical characteristics
(continued)**

Parameters	Min	Typ	Max	Unit	Comments
PSRR with 4.7uF output cap					
@ DC @noload			-40	dB	
@ DC @full load			-35		
Worst case @ any frequency			-12		

6.2.1.3 ULPREG electrical characteristics

Table 4. ULPREG electrical characteristics

Parameters	Min	Typ	Max	Unit	Comments
Power supply	3.0	3.3	3.6	V	
Current Consumption	1.88	2.3	2.86	μA	@ no load
	-	610	670	μA	@ full load
Output current capacity			20	mA	DC load current
Output voltage @ no load			1.175	V	
Output voltage @ full load	1.125			V	
PSRR with 500 pF output cap	-20			dB	Worst case at any frequency across corners
@ DC @noload			-50	dB	
@200KHz @noload			-37		
@ DC @full load			-42		
@200KHz @full load			-37		
Worst case @ any frequency @ any load			-15		

6.2.1.4 WBREG electrical characteristics

Table 5. WBREG electrical characteristics

Parameters	Min	Typ	Max	Unit	Comments
Power supply	3	3.3	3.6	V	-
Current Consumption	-	2	5	μA	@ no load
	-	2	5	μA	@ full load
Output current capacity	-	1	2	mA	DC load current
Output voltage @ no load		1.4	1.425	V	
Output voltage @ full load	1.375	1.398		V	
Output voltage programmability	1.4	1.4	1.7	V	16 steps of 25 mV each

Table 25. DDR3 mode DC Electrical characteristics (continued)

Symbol	Parameter	Test condition	Min	Typ	Max	Unit	Notes
Tri-state I/O supply current ³	lcc-ovdd	V _{in} = ovdd or 0			5		
Tri-state vdd2p5 supply current ³	lcc-vdd2p5	V _i = vddi or 0			1.5		
Tri-state core supply current ³	lcc-vddi				1		
Driver unit (240 Ohm) calibration resolution	Rres				10	Ohm	

1. The single-ended signals need to be within the respective limits (V_{ih}(dc) max, V_{il}(dc) min) for single-ended signals as well as the limitations for overshoot and undershoot.
2. V_{tt} is expected to track ovdd/2.
3. Typ condition: typ model, 1.5 V, and 25 °C. Max condition: bcs model, 1.575V, and -40 °C. Min condition: wcs model, 1.425V, and max T_j °C 125 °C junction

Table 26. LPDDR2 mode AC Electrical characteristics

Symbol	Parameter	Test condition	Min	Max	Unit	Notes
V _{ih} (ac)	AC input logic high		V _{ref} +0.22	ovdd	V	Note that the Jedec LPDDR2 specification (JESD209-2B) supersedes any specification in this document.
V _{il} (ac)	AC input logic low			V _{ref} -0.22	V	
V _{idh} (ac) ¹	AC differential input high voltage		0.44	-	V	
V _{idl} (ac) ¹	AC differential input low voltage			0.44	V	
V _{ix} (ac) ²	AC differential input crosspoint voltage	Relative to ovdd/2	-0.12	0.12	V	
V _{peak}	Over/undershoot peak			0.35	V	
V _{area}	Over/undershoot area (above ovdd or below ovss)	at 800MHz data rate		0.3	V*ns	
t _{sr}	Single output slew rate		0.4	2	V/ns	
t _{skd}	Skew between pad rise/fall asymmetry + skew caused by SSN			0.2	ns	

Table 32. 12-bit ADC Characteristics ($V_{REFH} = V_{DDAD}$, $V_{REFL} = V_{SSAD}$) (continued)

Characteristic	Conditions ¹	Symb	Min	Typ ²	Max	Unit	Comment
	ADLSMP=0 ADSTS=10			0.8			
	ADLSMP=0 ADSTS=11			0.85			
	ADLSMP=1 ADSTS=00			0.95			
	ADLSMP=1 ADSTS=01			1.05			
	ADLSMP=1 ADSTS=10			1.15			
	ADLSMP=1, ADSTS=11			1.25			
Total Unadjusted Error	12 bit mode	TUE	-2	-	+5	LSB ³	With Max Averaging
	10 bit mode		-0.5	-	+2		
	8 bit mode		-0.25	-	+1.5		
Differential Non-Linearity	12 bit mode	DNL	-	±0.6	±1.5	LSB ³	Waiting for histogram method confirmation
	10bit mode		-	±0.5	±1		
	8 bit mode		-	±0.25	±0.5		
Integral Non-Linearity	12 bit mode	INL	-	±2	±4	LSB ³	Waiting for histogram method confirmation
	10bit mode		-	±1	±2		
	8 bit mode		-	±0.5	±1		
Zero-Scale Error	12 bit mode	E _{ZS}	-	+1.0	±1.6	LSB ³	VADIN = V _{REFL} With Max Averaging
	10bit mode		-	±0.4	±0.8		
	8 bit mode		-	±0.1	±0.4		
Full-Scale Error	12 bit mode	E _{FS}	-	±2	±3.5	LSB ³	VADIN = V _{REFH} With Max Averaging
	10bit mode		-	±0.5	±1		
	8 bit mode		-	±0.25	±0.75		
Quantization Error	12 bit mode	E _Q	-	±1 to 0		LSB ³	
	10bit mode		-	±0.5			
	8 bit mode		-	±0.5			
Effective Number of Bits	12 bit mode	ENOB	10.1	10.7	-	Bits	Fin = 100Hz
Signal to Noise plus Distortion	See ENOB	SINAD	SINAD = 6.02 x ENOB + 1.76			dB	
Input Leakage Error	all modes	EIL	I _{in} x RAS			mV	I _{in} = 400 nA leakage current
Temp Sensor Slope	Across the full temperature range of the device	m	--	1.84	--	mV/°C	
Temp Sensor Voltage	25°C	V _{TEMP25}	-	696	-	mV	

1. All accuracy numbers assume the ADC is calibrated with $V_{REFH}=V_{DDAD}$
2. Typical values assume $V_{DDAD} = 3.0$ V, Temp = 25°C, $F_{adck}=20$ MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
3. $1 \text{ LSB} = (V_{REFH} - V_{REFL})/2N$

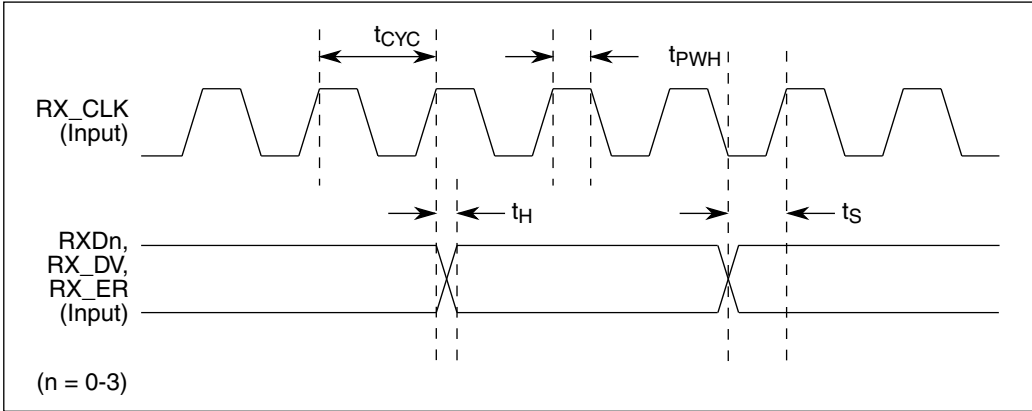


Figure 22. MII receive signal timing diagram

Table 42. Receive signal timing for MII interfaces

Characteristic		MII Mode			Unit
		Min	Typ	Max	
RX_CLK clock period (100/10 MBPS)	t_{CYC}		40/400		ns
RX_CLK duty cycle, t_{PWH}/t_{CYC}		45	50	55	%
Input setup time before RX_CLK	t_S	5			ns
Input hold time after RX_CLK	t_H	5			ns

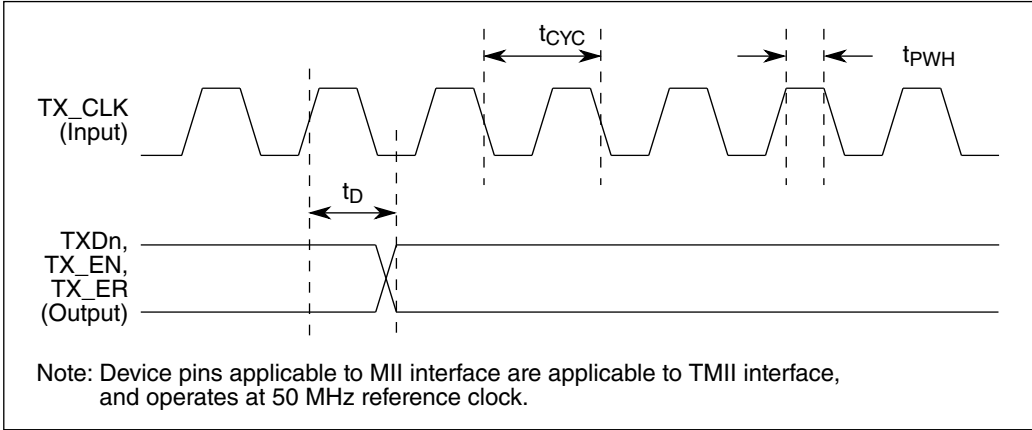


Figure 23. MII transmit signal timing diagram

Table 43. Transmit signal timing for MII interfaces

Characteristic		MII Mode			Unit
		Min	Typ	Max	
TX_CLK clock period (100/10 MBPS)	t_{CYC}		40/400		ns
TX_CLK duty cycle, t_{PWH}/t_{CYC}		45	50	55	%
Out delay from TX_CLK	t_D	2		25	ns

9.5 Memory interfaces

9.5.1 QuadSPI timing

- All data is based on a negative edge data launch from the device and a negative edge data capture, as shown in the timing diagrams in this section. This corresponds to the N/1 sample point as shown in the reference manual QSPI section "Internal Sampling of Serial Flash Input Data."
- Measurements are with a load of 35 pF on output pins. I/P Slew : 1ns
- Timings assume a setting of 0x0000_000x for QSPI_SMPR register (see the reference manual for details).

SDR mode

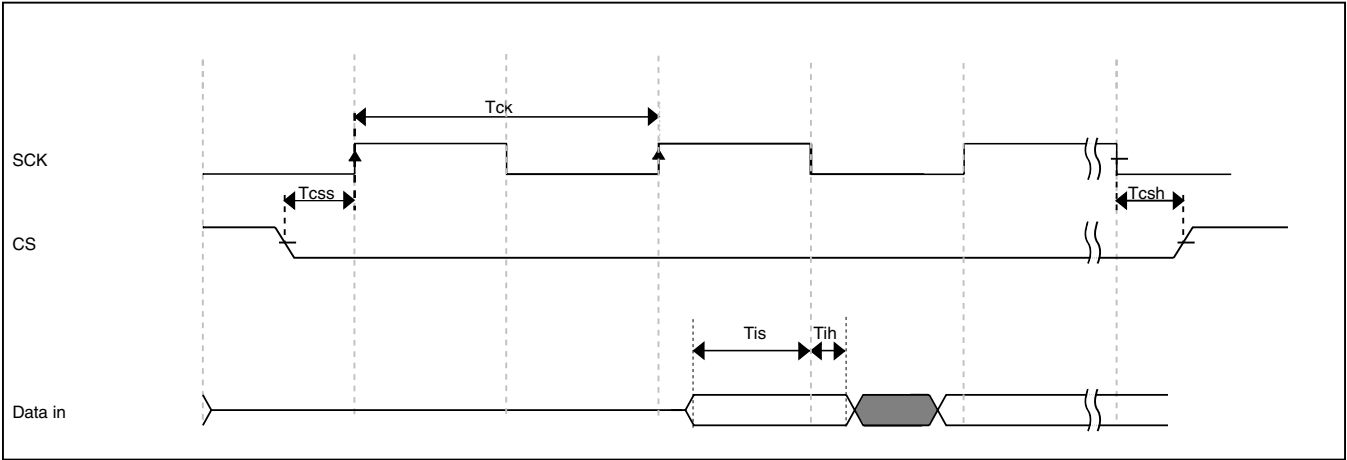


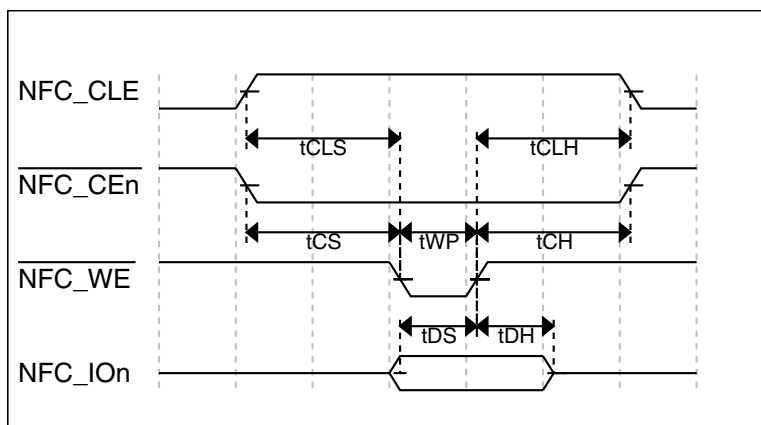
Figure 30. QuadSPI Input/Read timing (SDR mode)

Table 48. QuadSPI Input/Read timing (SDR mode)

Symbol	Parameter	Value		Unit
		Min	Max	
T_{is}	Setup time for incoming data	4.5	—	ns
T_{ih}	Hold time requirement for incoming data	0	—	ns

Table 52. NFC specifications

Num	Description	Min.	Max.	Unit
t_{CLS}	NFC_CLE setup time	$2T_H + T_L - 1$	—	ns
t_{CLH}	NFC_CLE hold time	$T_H + T_L - 1$	—	ns
t_{CS}	$\overline{\text{NFC_CEn}}$ setup time	$2T_H + T_L - 1$	—	ns
t_{CH}	$\overline{\text{NFC_CEn}}$ hold time	$T_H + T_L$	—	ns
t_{WP}	$\overline{\text{NFC_WP}}$ pulse width	$T_L - 1$	—	ns
t_{ALS}	NFC_ALE setup time	$2T_H + T_L$	—	ns
t_{ALH}	NFC_ALE hold time	$T_H + T_L$	—	ns
t_{DS}	Data setup time	$T_L - 1$	—	ns
t_{DH}	Data hold time	$T_H - 1$	—	ns
t_{WC}	Write cycle time	$T_H + T_L - 1$	—	ns
t_{WH}	$\overline{\text{NFC_WE}}$ hold time	$T_H - 1$	—	ns
t_{RR}	Ready to $\overline{\text{NFC_RE}}$ low	$4T_H + 3T_L + 90$	—	ns
t_{RP}	$\overline{\text{NFC_RE}}$ pulse width	$T_L + 1$	—	ns
t_{RC}	Read cycle time	$T_L + T_H - 1$	—	ns
t_{REH}	$\overline{\text{NFC_RE}}$ high hold time	$T_H - 1$	—	ns
t_{IS}	Data input setup time	11	—	ns


Figure 34. Command latch cycle timing

9.5.4.2 DDR3 Read Cycle

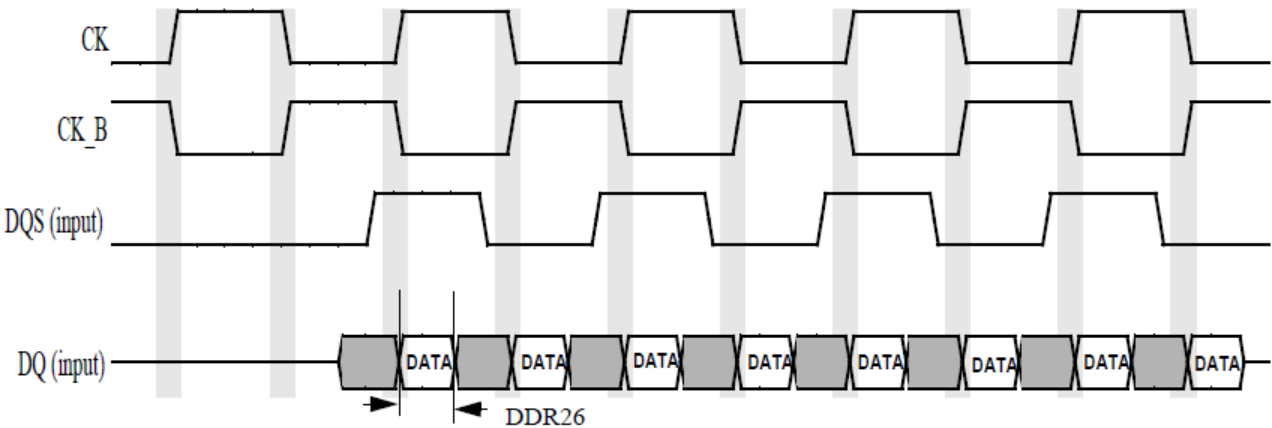


Figure 42. DDR3 Read Cycle

Table 55. DDR3 Read Cycle

ID	Parameter	Symbol	CK = 400 MHz		Unit
			Min	Max	
DDR26	Minimum required DQ valid window width	-	750	-	ps

NOTE

To receive the reported setup and hold values, read calibration should be performed in order to locate the DQS in the middle of DQ window.

NOTE

All measurements are in reference to Vref level.

NOTE

Measurements were done using balanced load and 25 ohms resistor from outputs to VDD_REF

9.5.4.3 DDR3 Write cycle

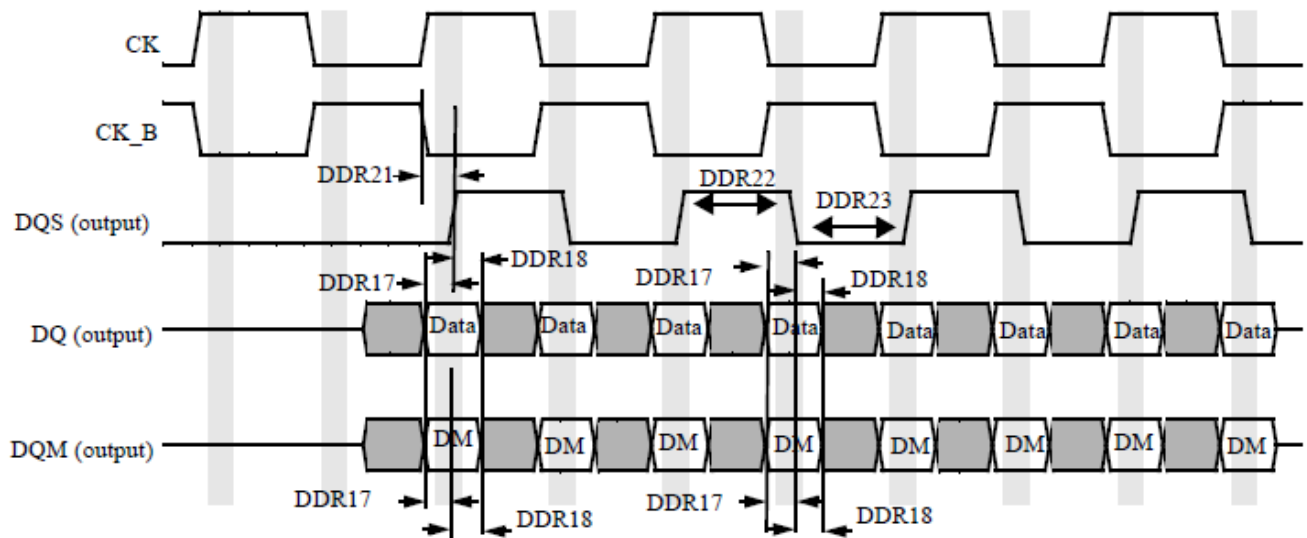


Figure 43. DDR3 Write cycle

Table 56. DDR3 Write cycle

ID	Parameter	Symbol	CK = 400 MHz		Unit
			Min	Max	
DDR17	DQ and DQM setup time to DQS (differential strobe)	tDS	240	—	ps
DDR18	DQ and DQM hold time to DQS (differential strobe)	tDH	215	—	ps
DDR21	DQS latching rising transitions to associated clock edges	tDQSS	-0.25	+0.25	tCK
DDR22	DQS high level width	tDQSH	0.45	0.55	tCK
DDR22	DQS low level width	tDQSL	0.45	0.55	tCK

NOTE

To receive the reported setup and hold values, write calibration should be performed in order to locate the DQS in the middle of DQ window.

NOTE

All measurements are in reference to Vref level.

NOTE

Measurements were done using balanced load and 25 ohms resistor from outputs to VDD_REF.

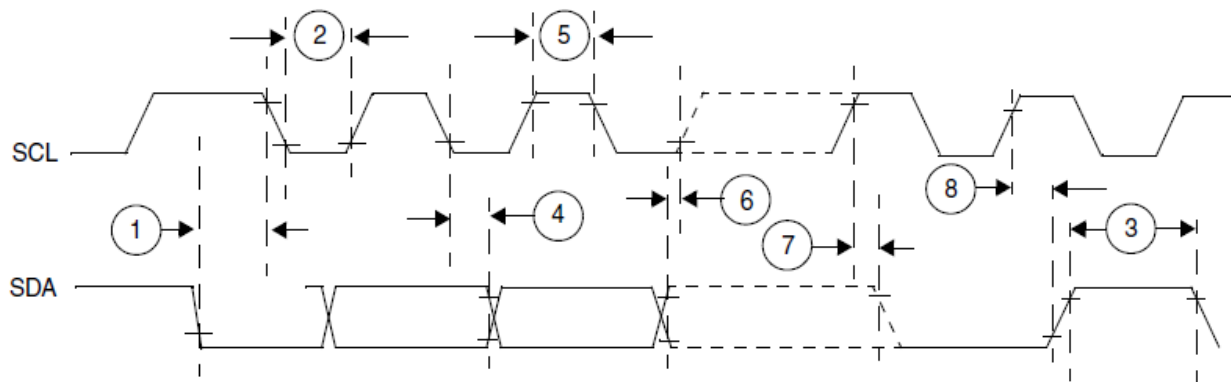


Figure 51. I2C input/output timing

9.6.3 SDHC specifications

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the physical interface. A load of 50 pF is assumed.

Table 63. SDHC switching specifications

Num	Symbol	Description	Min.	Max.	Unit
		Operating voltage	1.71	3.6	V
		Card input clock			
SD1	fpp	Clock frequency (low speed)	0	400	kHz
	fpp	Clock frequency (SD\SDIO full speed\high speed)	0	25\50	MHz
	fpp	Clock frequency (MMC full speed\high speed)	0	20\50	MHz
	f _{OD}	Clock frequency (identification mode)	0	400	kHz
SD2	t _{WL}	Clock low time	7	—	ns
SD3	t _{WH}	Clock high time	7	—	ns
SD4	t _{TLH}	Clock rise time	—	3	ns
SD5	t _{THL}	Clock fall time	—	3	ns
		SDHC output / card inputs SDHC_CMD, SDHC_DAT (reference to SDHC_CLK)			
SD6	t _{OD}	SDHC output delay (output valid)	-5	4	ns
		SDHC input / card inputs SDHC_CMD, SDHC_DAT (reference to SDHC_CLK)			
SD7	t _{ISU}	SDHC input setup time	5	—	ns
SD8	t _{IH}	SDHC input hold time	0	—	ns

Table 66. Fast internal oscillator electrical characteristics (continued)

Symbol	Parameter	Condition ¹	Value			Unit
			Min	Typ	Max	
RCMVAR	RC oscillator variation in temperature and supply with respect to f_{RC} at $T_A = 55\text{ }^{\circ}\text{C}$ in high frequency configuration		-5		+5	%

1. $V_{DD} = 1.2\text{ V}$, $T_A = -40\text{ to }+85\text{ }^{\circ}\text{C}$, unless otherwise specified.

9.7.4 Slow internal RC oscillator (128 KHz) electrical characteristics

This section describes a slow internal RC oscillator (SIRC). This can be used as the reference clock for the RTC module.

Table 67. Slow internal RC oscillator electrical characteristics

Symbol	Parameter	Condition ¹	Value			Unit
			Min	Typ	Max	
f_{RCL}	RC oscillator low frequency	$T_A = 25\text{ }^{\circ}\text{C}$, trimmed	—	128	—	kHz
I_{RCL}	RC oscillator low frequency current	$T_A = 25\text{ }^{\circ}\text{C}$, trimmed	—	3.1		μA
RCLTRIM	RC oscillator precision after trimming of f_{RCL}	$T_A = 25\text{ }^{\circ}\text{C}$	-1	—	+1	%
RCLVAR 3	RC oscillator variation in temperature and supply with respect to f_{RC} at $T_A = 55\text{ }^{\circ}\text{C}$ in high frequency configuration	High frequency configuration	-5	—	+5	%

1. $V_{DD} = 1.2\text{ V}$, $T_A = -40\text{ to }+85\text{ }^{\circ}\text{C}$, unless otherwise specified.

9.7.5 PLL1 and PLL2 (528 MHz System PLL) Electrical Parameters

Table 68. PLL1 and PLL2 Electrical Parameters

Parameter	Value
Clock output range	528 MHz PLL output
Reference clock	24 MHz
Lock time	<7500 reference cycles
Period jitter(p2p)	<140ps
Duty Cycle	48.9%~51.7% PLL output

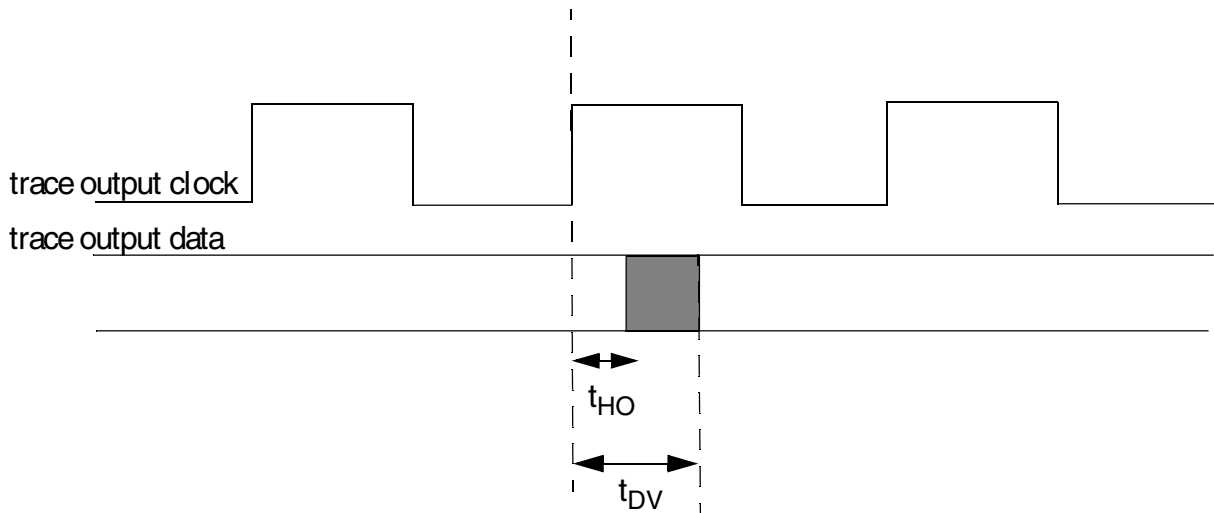


Figure 57. Trace data specifications

10 Thermal attributes

10.1 Thermal attributes

Board type	Symbol	Description	176LQFP	Unit	Notes
Single-layer (1s)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	50	$^{\circ}\text{C}/\text{W}$	1, 2
Four-layer (2s2p)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	32	$^{\circ}\text{C}/\text{W}$	1,3
Single-layer (1s)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	40	$^{\circ}\text{C}/\text{W}$	1, 3
Four-layer (2s2p)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	25	$^{\circ}\text{C}/\text{W}$	1, 3
—	$R_{\theta JB}$	Thermal resistance, junction to board	21	$^{\circ}\text{C}/\text{W}$	4
—	$R_{\theta JCtop}$	Thermal resistance, junction to case top	12	$^{\circ}\text{C}/\text{W}$	5
—	Ψ_{JT}	Thermal characterization parameter, junction	3	$^{\circ}\text{C}/\text{W}$	6

Dimensions

5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

11 Dimensions

11.1 Obtaining package dimensions

Package dimensions are provided in package drawing.

To find a package drawing, go to www.freescale.com and perform a keyword search for the drawing's document number:

Package	Freescale Document Number
176-pin LQFP	98ASA00452D
364 MAPBGA	98ASA00418D

12 Pinouts

12.1 Pinouts

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The IOMUX Controller (IOMUXC) Module is responsible for selecting which ALT functionality is available on each pin.

NOTE

The 176 LQFP parts are not pin compatible between the F-Series and R-Series families.

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
Y2	—	ADC0SE8	N/A		ADC0_SE8							
W2	—	ADC0SE9			ADC0_SE9							
W3	—	ADC1SE8			ADC1_SE8							
Y3	—	ADC1SE9			ADC1_SE9							
W1	41	VREFH_ADC			VREFH_ADC							
U3	40	VREFL_ADC			VREFL_ADC							

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
U14	74	EXT_TAMPER1			EXT_TAMPER1							
T13	—	EXT_TAMPER2/ EXT_WM0_TAMPER_IN			EXT_TAMPER2/ EXT_WM0_TAMPER_IN							
U13	—	EXT_TAMPER3/ EXT_WM0_TAMPER_OUT			EXT_TAMPER3/ EXT_WM0_TAMPER_OUT							
U12	—	EXT_TAMPER4/ EXT_WM1_TAMPER_IN			EXT_TAMPER4/ EXT_WM1_TAMPER_IN							
U10	—	EXT_TAMPER5/ EXT_WM1_TAMPER_OUT			EXT_TAMPER5/ EXT_WM1_TAMPER_OUT							
G7	2	VDD			VDD							
J7	—	VDD			VDD							
L7	22	VDD			VDD							
H8	48	VDD			VDD							
K8	85	VDD			VDD							
M8	102	VDD			VDD							
P8	125	VDD			VDD							
G9	136	VDD			VDD							
N9	174	VDD			VDD							
H10	—	VDD			VDD							
P10	—	VDD			VDD							
G11	—	VDD			VDD							
N11	—	VDD			VDD							
H12	—	VDD			VDD							
P12	—	VDD			VDD							
G13	—	VDD			VDD							
J13	—	VDD			VDD							
L13	—	VDD			VDD							
N13	—	VDD			VDD							
H14	—	VDD			VDD							
K14	—	VDD			VDD							
M14	—	VDD			VDD							
P14	—	VDD			VDD							
A1	1	VSS			VSS							
A20	13	VSS			VSS							

**Table 78. Functional Assignment Pins
(continued)**

Signal Name	364 MAP BGA	176 LQFP (F-series ONLY)	Power Group	Pad Type	Default Mode (Reset)	Default Function	Input/Output	Value
PTC7	N2	17	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC8	N4	18	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC9	T15	77	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC10	U15	78	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC11	P4	20	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC12	P3	21	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC13	P1	23	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC14	R1	26	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC15	P2	27	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC16	R3	29	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC17	R4	28	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC26	D16	153	VDD33	GPIO	ALT3	RCON24	Input	Disabled
PTC27	E16	154	VDD33	GPIO	ALT3	RCON25	Input	Disabled
PTC28	E15	155	VDD33	GPIO	ALT3	RCON26	Input	Disabled
PTC29	C16	152	VDD33	GPIO	ALT3	RCON27	Input	Disabled
PTC30	T8	58	VDD33	GPIO	ALT3	RCON28	Input	Disabled
PTC31	W5	42	VDD33	GPIO	ALT3	RCON29	Input	Disabled
PTD0	Y17	86	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD1	Y18	87	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD2	V18	88	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD3	Y19	89	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD4	W19	90	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD5	W20	91	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD6	V20	92	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD7	V19	93	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD8	U17	94	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD9	U18	97	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD10	U20	98	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD11	T20	99	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD12	T19	100	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD13	T18	101	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD16	D20	133	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD17	E20	132	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD18	E18	131	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD19	F16	130	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD20	F17	129	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD21	F19	128	VDD33	GPIO	ALT0	GPIO	Disabled	

Table continues on the next page...

**Table 78. Functional Assignment Pins
(continued)**

Signal Name	364 MAP BGA	176 LQFP (F-series ONLY)	Power Group	Pad Type	Default Mode (Reset)	Default Function	Input/Output	Value
PTD22	F20	126	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD23	G20	124	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD24	G19	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD25	G18	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD26	G16	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD27	H16	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD28	H17	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD29	H18	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD30	H20	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTD31	J20	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE0	N16	103	VDD33	GPIO	ALT2	BMODE1	Input	Disabled
PTE1	N18	104	VDD33	GPIO	ALT2	BMODE0	Input	Disabled
PTE2	N19	105	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE3	Y15	80	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE4	N20	106	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE5	T16	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE6	W16	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE7	M20	109	VDD33	GPIO	ALT3	RCON0	Input	Disabled
PTE8	M19	110	VDD33	GPIO	ALT3	RCON1	Input	Disabled
PTE9	M17	111	VDD33	GPIO	ALT3	RCON2	Input	Disabled
PTE10	M16	112	VDD33	GPIO	ALT3	RCON3	Input	Disabled
PTE11	L16	113	VDD33	GPIO	ALT3	RCON4	Input	Disabled
PTE12	L17	114	VDD33	GPIO	ALT3	RCON5	Input	Disabled
PTE13	Y16	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE14	W15	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE15	L18	115	VDD33	GPIO	ALT3	RCON6	Input	Disabled
PTE16	L20	116	VDD33	GPIO	ALT3	RCON7	Input	Disabled
PTE17	K20	117	VDD33	GPIO	ALT3	RCON8	Input	Disabled
PTE18	K19	118	VDD33	GPIO	ALT3	RCON9	Input	Disabled
PTE19	K18	119	VDD33	GPIO	ALT3	RCON10	Input	Disabled
PTE20	A12	170	VDD33	GPIO	ALT3	RCON11	Input	Disabled
PTE21	V16	81	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE22	W17	84	VDD33	GPIO	ALT0	GPIO	Disabled	
PTE23	J17	122	VDD33	GPIO	ALT3	RCON12	Input	Disabled
PTE24	D19	134	VDD33	GPIO	ALT3	RCON13	Input	Disabled
PTE25	C19	135	VDD33	GPIO	ALT3	RCON14	Input	Disabled
PTE26	C20	137	VDD33	GPIO	ALT3	RCON15	Input	Disabled

Table continues on the next page...

Table 79. Revision History

Rev. No.	Date	Substantial Changes
		Added Part Number Format figure Updated the Fields table as per the device part numbers Added Part Numbers table Added External NPN Ballast section In the LVD Dig Electrical Specs, minimum value of Upper Voltage Threshold and Lower Voltage threshold In the FlexBus timing specifications table, clarified the Frequency of operation In the Power consumption, filled TBDs. Updated footnotes Rewritten the EMC radiated emissions operating behaviors table In the GPIO DC Electrical characteristics table: • V_{hys} test condition changed • Added R_Keeper row In the DDR operating conditions, changed the V_{ddi} Min and Max values In the Power sequencing table, removed some rows In the Power Supply section, removed LVDS and removed the note In the Recommended operating conditions table, updated min and max of VDD12_AFE and FA_VDD. Updated Min, Max, and Typ for VDD Added the Recommended Connections for Unused Analog Interfaces table In the 12-bit ADC Characteristics table, updated the typ and max values of TUE, DNL, INL, ZSE, FSE Added Receive and Transmit signal timing specifications for MII interfaces In the DSPI table, clarified the TBDs In PLL 4, PLL 5, PLL 6 electrical characteristics tables, added footnotes In the JTAG electrical table, clarified the TBDs In the pinouts section, added Special Signal table Added Power Supply pins section Added Functional Assignment section

Table continues on the next page...

Table 79. Revision History (continued)

Rev. No.	Date	Substantial Changes
		in 12-bit ADC operating conditions section - Updated figures for clarity in "12-bit DAC operating behaviors" section - Updated figure "VideoADC supply scheme" in "VideoADC Specifications" section - Editorial updates throughout
Rev 8	November 2014	- In "Part number format" figure, updated explanation for '1'. - In "Fields" table, updated definition of 'R'. - In "External NPN ballast" section, updated recommendations for transistor selection. - In "DDR parameters" section, updated table footnotes regarding typical condition. - In "Power sequencing" table, added comment regarding SDRAMC_VDD1P5: "In case the Ballast transistor's collector is connected to the 1.5 V DRAM supply (instead of the 3.3 V supply), turn this 1.5 V supply on before turning on the 3.3V." - In "VideoADC specifications" table, added supply current values. - In "Receive and Transmit signal timing specifications," added the following note: "See the most current errata document when using the internally generated RXCLK and TXCLK clocks." - Updated "QuadSPI timing" section, presenting data based on a negative edge data launch from the device and a negative edge data capture; updated the figure, "QuadSPI Input/Read timing (SDR mode)"; updated the table, "QuadSPI Input/Read timing (SDR mode)." - For the "SDHC switching specifications" table, added the statement, "A load of 50 pF is assumed"; updated max value for SD6, SDHC output delay (output valid). - In the "24 MHz oscillator specifications" section, added the statement, "The crystal must be rated for a drive level of 250 μW or higher. An ESR (equivalent series

How to Reach Us:**Home Page:**freescale.com**Web Support:**freescale.com/support

Information in this document is provided solely to enable system and software implementers to use Freescale products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits based on the information in this document.

Freescale reserves the right to make changes without further notice to any products herein.

Freescale makes no warranty, representation, or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages.

“Typical” parameters that may be provided in Freescale data sheets and/or specifications can and do vary in different applications, and actual performance may vary over time. All operating parameters, including “typicals,” must be validated for each customer application by customer's technical experts. Freescale does not convey any license under its patent rights nor the rights of others. Freescale sells products pursuant to standard terms and conditions of sale, which can be found at the following address: freescale.com/SalesTermsandConditions.

Freescale and the Freescale logo are trademarks of Freescale Semiconductor, Inc., Reg. U.S. Pat. & Tm. Off. Vybrid is a trademark of Freescale Semiconductor, Inc. All other product or service names are the property of their respective owners. ARM and Cortex are registered trademarks of ARM Limited. NEON is the trademark of ARM Limited.

© 2012–2013 Freescale Semiconductor, Inc.